



# Specification for Approval

Date: 2015/03/17

Customer: 群創

TAI-TECH P/N: HPC5024BV-220M-C

CUSTOMER P/N:

DESCRIPTION:

QUANTITY: pcs

REMARK:

Customer Approval Feedback

西北臺慶科技股份有限公司 TAI-TECH Advanced Electronics Co., Ltd

#### ■ 西北臺慶科技股份有限公司

TAI-TECH Advanced Electronics Co., Ltd

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| APPROVED  | CHECKED   | DRAWN     |
|-----------|-----------|-----------|
| 楊祥忠       | 詹偉特       | 何秦芝       |
| Mike Yang | Jack Chan | Sharon Ho |

|     |          | ECN HISTORY | LIST     |         |       |
|-----|----------|-------------|----------|---------|-------|
| REV | DATE     | DESCRIPTION | APPROVED | CHECKED | DRAWN |
| 1.0 | 15/03/17 | 新 發 行       | 楊祥忠      | 詹偉特     | 何秦芝   |
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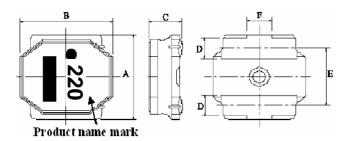
#### 1. Features

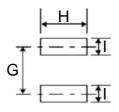
- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant
- 3. High reliability -Reliability test complied to AEC-Q200





#### 2. Dimension





| Series    | A(mm)   | B(mm)   | C(mm)    | D(mm)   | E(mm)   | F(mm)    | G(mm)    | H(mm)    | l(mm)    |
|-----------|---------|---------|----------|---------|---------|----------|----------|----------|----------|
| HPC5024BV | 4.9±0.2 | 4.9±0.2 | 2.4 max. | 1.2±0.2 | 3.3±0.2 | 1.3 typ. | 3.6 ref. | 4.0 ref. | 1.5 ref. |

Units: mm

### 3. Part Numbering

| <b>HPC</b> | <b>5024</b> | BV | - | <b>220</b> | M | - | C |
|------------|-------------|----|---|------------|---|---|---|
| Α          | В           | С  |   | D          | Е |   | F |

- A: Series
- B: Dimension
- C: Control S/N
- D: Inductance 220=22uH
  E: Inductance Tolerance M=±20%
- F: Control S/N

| TAI-TECH<br>Part Number | Inductance<br>(uH) | Tolerance (%) | Test<br>Frequency<br>(Hz) | SRF<br>(MHz) min. | DCR<br>(Ω) ±20% | I sat<br>(A) typ | I sat<br>(A) max | I rms<br>(A) typ | I rms<br>(A) max |
|-------------------------|--------------------|---------------|---------------------------|-------------------|-----------------|------------------|------------------|------------------|------------------|
| HPC5024BV-220M-C        | 22                 | ±20%          | 1V100K                    | 15                | 0.230           | 1.50             | 1.35             | 1.35             | 1.20             |

#### 層測條件

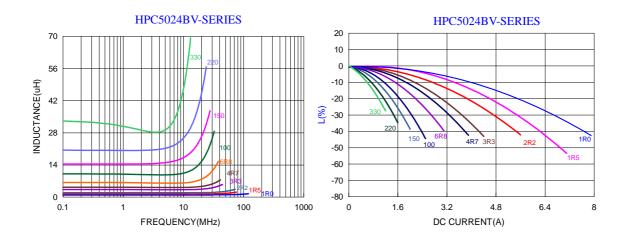
| Part Number      | Impulse Tester<br>電壓(V) | 面積比較<br>(%) | 面積差比較<br>(%) | 放電量比較 | 二次微分 | 層測設備廠陪型號                            |
|------------------|-------------------------|-------------|--------------|-------|------|-------------------------------------|
| HPC5024BV-220M-C | 165                     | 5           | 15           | 330   | 4    | Chroma Impusle Winding Tester 19301 |

Note:

Shipping frequency: 1MHz / 1.0V

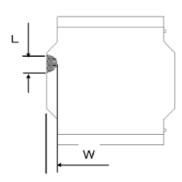
 $\mbox{Isat}: \mbox{Based on inductance change} \quad (\, \triangle \mbox{L/L0}: \, {\leq} \mbox{-30\%} \,) \, \, @ \, \, \mbox{ambient temp.} \, 25\%$ 

Irms : Based on temperature rise  $(\triangle T : 40^{\circ}C \text{ typ.})$ 



#### **Core chipping**

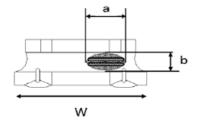
The appearance standard of the chipping size on top side, and bottom side ferrite core is listed below.



| Туре      | L          | w          |
|-----------|------------|------------|
| HPC5024BV | 1.5mm Max. | 1.5mm Max. |

#### **Void appearance tolerance Limit**

Size of voids occurring to coating resin is specified below.



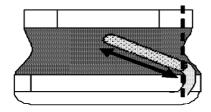
Exposed wire tolerance limit of coating resin part on product side.

Size of exposed wire occurring to coating resin is specified below.

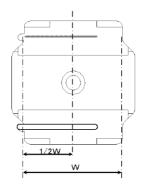
- Width direction (dimension a): Acceptable when a≤w/2
   Nonconforming when a>w/2
- 2. Length direction (dimension b): Dimension b is not specified.
- 3. The total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, and is acceptable.

External appearance criterion for exposed wire

Exposed end of the winding wire at the secondary side should be 3mm and below.

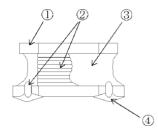


## 5. Exectrde appearance criterion for exposed wire



| Cross section of joint part  | Appearance judgment   |
|--|---|
| Only top side of wire is exposed. (regardless of whole tope side of wire exposed)            | Good  |
| Wire is soldered insufficiently and less than half of outer diameter is covered with solder. | Less than half of width of insufficiently soldered portion shall be acceptable. (More than half shall be segregated as reject.) |

### 6. Material List



| No. | Item    | Material            |
|-----|---------|---------------------|
| 1   | Core    | Ni-Zn ferrite       |
| 2   | Wire    | Copper Wire         |
| 3   | Coating | Epoxy with magnetic |
| 4   | Solder  | Lead free           |

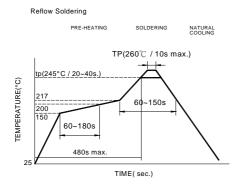
## 7. Reliability and Test Condition

| Item                                  | Performance  | Test Condition   |  |  |  |  |
|---------------------------------------|--|--|--|--|--|--|
| Operating temperature                 | -40~+125°C   |  |  |  |  |  |
| Storage temperature and               |  |  |  |  |  |  |
| Humidity range                        | -40~+125℃ (on board)   |  |  |  |  |  |
| Electrical Performance Te             | st   |  |  |  |  |  |
|                                       |  | HP4284A,CH11025,CH3302,CH1320,CH1320S  |  |  |  |  |
| Inductance                            | Refer to standard electrical characteristics list.   | LCR Meter.   |  |  |  |  |
| DCR                                   |  | CH16502,Agilent33420A Micro-Ohm Meter.   |  |  |  |  |
|                                       |  | Saturation DC Current (Isat) will cause L0   |  |  |  |  |
| Saturation Current (Isat)             | △L≦30% typical.  | to drop △L(%)(keep quickly).   |  |  |  |  |
|                                       |  | Heat Rated Current (Irms) will cause the coil temperature  |  |  |  |  |
|                                       |  | rise $\triangle T(^{\circ}C)$ without core loss.   |  |  |  |  |
| Heat Rated Current (Irms)             | Approximately △T≦40°C  | 1.Applied the allowed DC current(keep 1 min.).   |  |  |  |  |
|                                       |  | 2.Temperature measured by digital surface thermometer  |  |  |  |  |
| Reliability Test                      | Reliability Test   |  |  |  |  |  |
| High Temperature<br>Exposure(Storage) | Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value | Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Temperature : 125±2°ℂ (Bead) Temperature : 85±2°ℂ (Inductor) Duration : 1000hrs Min. Measured at room temperature after placing for 24±2 hrs |  |  |  |  |

| Item                                       | Performance   | Test Condition  |
|--|---|---|
| Temperature Cycling                        |   | Preconditioning: Run through IR reflow for 2 times, (IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -55±2°C 30min Min.(Bead) Step1: -40±2°C 30min Min.(Inductor) Step2: 125±2°C transition time 1min MAX. Step3: 125±2°C 30min Min. Step4: Low temp. transition time 1 min MAX. Number of cycles: 1000 Measured at room temperature after placing for 24±2 hrs |
| Biased Humidity                            | Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within±15% of initial value and shall not exceed the specification value | Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±3% R.H, Temperature: 85°C±2°C Duration: 1000hrs Min with 100% rated current. Measured at room temperature after placing for24±2 hrs   |
| High<br>Temperature<br>Operational<br>Life |   | Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Temperature : 125±2°C (Bead) Temperature : 85±2°C (Inductor) Duration : 1000hrs Min. with 100% rated current. Measured at room temperature after placing for24±2 hrs  |
| Vibration                                  |   | Oscillation Frequency: 10~2K~10Hz for 20 minute Equipment: Vibration checker Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations) °  |
| Resistance to<br>Soldering Heat            |   | Number of heat cycles: 1  Temperature(°C) Time(s) Temperature ramp/immersion and emersion rate  260±5(solder temp) 10±1 25mm/s ±6 mm/s  |
| Thermal shock                              |   | Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -55±2℃ 15±1min(Inductor) Step1: -40±2℃ 15±1min(Inductor) Step2: 125±2℃ within 20Sec. Step3: 125±2℃ 15±1min Number of cycles: 300 Measured at room temperature after placing fo24±2hrs  |
| ESD  | Appearance: No damage.  | Votage  Votage  T <sub>C</sub> = charge tine constant  T <sub>d</sub> = discharge tine constant  T <sub>d</sub> = discharge tine constant  Ine  to charge tine  to charge tine  to charge tine  to charge tine  |
| Solderability                              | More than 95% of the terminal electrode should be covered with solder ∘   | Steam Aging: 8 hours ± 15 min Preheat: 150°C,60sec. ° Solder: Sn99.5%-Cu0. 5% ° Temperature: 245±5°C ° Flux for lead free: Rosin. 9.5% ° Dip time: 4±1sec. Depth: completely cover the termination  |

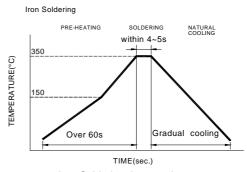
| Item             | Performance            | Test Condition   |
|------------------|------------------------|--|
|                  |                        | Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Place the 100mm X 40mm board into a fixture similar to the one shown in below Figure with the component facing down. The apparatus shall consist of mechanical means to apply a force which will bend the board (D) x = 2 mm minimum. The duration of the applied forces shall be 60 (+ 5) sec. The force is to be applied only once to the board. |
| Board Flex       |                        | 45+2 45+2 4522-4   |
|                  | Appearance: No damage. | Probe to exect bursting finos  Radius 340  Printed circuit board under test  Displacement  |
| Terminal         |                        | Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020D Classification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a 17.7 N (1.8 Kg) force to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to thecomponent being tested.  |
| Strength ( SMD ) |                        | substrate press tool shear force   |

## 8. Soldering



Reflow times: 3 times max.

Fig.1



Iron Soldering times: 1 times max.

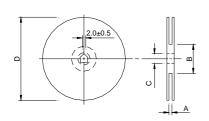
Fig.2

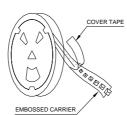
TAI-TECH P1

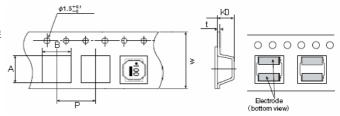
(2) Tape Dimension

### 9. Packaging Information

#### (1) Reel Dimension







| Туре      | A(mm)    | B(mm)  | C(mm)  | D(mm)   |
|-----------|----------|--------|--------|---------|
| HPC5024BV | 13.5±1.5 | 80±2.0 | 13±0.5 | 330±3.0 |

| Туре      | A(mm)    | B(mm)    | Ko(mm)  | P(mm)   | W(mm)  | t(mm)   |
|-----------|----------|----------|---------|---------|--------|---------|
| HPC5024BV | 5.25±0.1 | 5.25±0.1 | 2.7±0.1 | 8.0±0.1 | 12±0.3 | 0.3±0.1 |

#### (3) Packaging Quantity

| Туре      | Chip / Reel |  |
|-----------|-------------|--|
| HPC5024BV | 2500        |  |

#### **Application Notice**

- Storage Conditions(component level)
- To maintain the solderability of terminal electrodes: 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: Less than 40  $^{\circ}\mathrm{C}^{\phantom{\circ}}$  and 60% RH.
- Recommended products should be used within 12 months form the time of delivery.
   The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



號碼(No.): CE/2014/B1174 日期(Date): 2014/11/17

頁数(Page): 1 of 15

## **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

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(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

SMD POWER INDUCTOR

樣品型號(Style/Item No.)

HPC(YHC, DR), MDC, FPC(YPC), FWP, SPC, SPI, UHP, DFP, DHP, TLPC, TLPH,

TLI SERIES

收件日期(Sample Receiving Date)

2014/11/10

測試期間(Testing Period)

2014/11/10 TO 2014/11/17

測試結果(Test Results) :

請見下一頁 (Please refer to next pages).



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頁數(Page): 2 of 15

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(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA) (桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

#### 測試結果(Test Results)

測試部位(PART NAME)No.1

: 整體混測 (MIXED ALL PARTS)

| 測試項目<br>(Test Items)             | 單位<br>(Unit) | 測試方法<br>(Method)   | 方法偵測<br>極限値<br>(MDL) | 結果<br>(Result)<br>No.1 |
|----------------------------------|--------------|--|----------------------|------------------------|
| 鎬 / Cadmium (Cd)                 | mg/kg        | 參考IEC 62321-5: 2013方法, 以感應耦合<br>電漿原子發射光譜儀檢測. / With<br>reference to IEC 62321-5: 2013 and<br>performed by ICP-AES. | 2                    | n.d.                   |
| 鋁 / Lead (Pb)                    | mg/kg        | 参考IEC 62321-5: 2013方法, 以感應耦合<br>電漿原子發射光譜儀檢測. / With<br>reference to IEC 62321-5: 2013 and<br>performed by ICP-AES. | 2                    | n.d.                   |
| 汞 / Mercury (Hg)                 | mg/kg        | 參考IEC 62321-4: 2013方法, 以感應耦合<br>電漿原子發射光譜儀檢測. / With<br>reference to IEC 62321-4: 2013 and<br>performed by ICP-AES. | 2                    | n.d.                   |
| 六價鉻 / Hexavalent Chromium Cr(VI) | mg/kg        | 参考IEC 62321: 2008方法,以UV-VIS檢<br>測. / With reference to IEC 62321:<br>2008 and performed by UV-VIS.                 | 2                    | n.d.                   |
| 绨 / Antimony (Sb)                | mg/kg        | 參考US EPA 3052方法,以感應耦合電漿原子發射光譜儀檢測./With reference to US EPA Method 3052. Analysis was performed by ICP-AES.         | 2                    | n.d.                   |
| 鈹 / Beryllium (Be)               | mg/kg        | 参考US EPA 3052方法,以感應耦合電漿原子發射光譜儀檢測./With reference to US EPA Method 3052. Analysis was performed by ICP-AES.         | 2                    | n.d.                   |

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(耀鑽科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

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| 測試項目<br>(Test Items)   | 單位<br>(Unit) | 測試方法<br>(Method)  | 方法偵測<br>極限値<br>(MDL) | 結果<br>(Result) |
|--|--------------|---|----------------------|----------------|
| (Tost Items)   | (Onit)       | (Method)  |                      | No.1           |
| 鄰苯二甲酸丁苯甲酯 / BBP (Butyl<br>Benzyl phthalate) (CAS No.: 85-68-7)                     | %            | 参考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.003                | n.d.           |
| 鄰苯二甲酸二 (2-乙基己基)酯 / DEHP<br>(Di- (2-ethylhexyl) phthalate) (CAS<br>No.: 117-81-7)   | %            | 参考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.003                | n.d.           |
| 鄰苯二甲酸二異癸酯 / DIDP (Di-<br>isodecyl phthalate) (CAS No.: 26761-<br>40-0; 68515-49-1) | %            | 参考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.01                 | n.d.           |
| 鄰苯二甲酸二異壬酯 / DINP (Di-<br>isononyl phthalate) (CAS No.: 28553-<br>12-0; 68515-48-0) | %            | 参考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.01                 | n.d.           |
| 鄰苯二甲酸二正辛酯 / DNOP (Di-n-<br>octyl phthalate) (CAS No.: 117-84-0)                    | %            | 參考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.003                | n.d.           |
| 鄰苯二甲酸二丁酯 / DBP (Dibutyl<br>phthalate) (CAS No.: 84-74-2)                           | %            | 參考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.003                | n.d.           |
| 鄰苯二甲酸二異丁酯 / DIBP (Di-<br>isobutyl phthalate) (CAS No.: 84-69-<br>5)                | %            | 參考EN 14372, 以氣相層析/質譜儀檢測.<br>/ With reference to EN 14372.<br>Analysis was performed by GC/MS. | 0.003                | n.d.           |
| 聚氟乙烯 / PVC   | **           | 以紅外光譜分析及焰色法檢測./<br>Analysis was performed by FTIR and<br>FLAME Test.                          | -                    | Negative       |

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日期(Date): 2014/11/17

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# **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(耀鑚科技股份有限公司 / YOSONIC TECHNOLOGY CO., LTD.)

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| 測試項目<br>(Test Items)  | 單位<br>(Unit) | 測試方法<br>(Method)  | 方法偵測<br>極限値 | 結果<br>(Result) |
|---|--------------|---|-------------|----------------|
| 全氟辛烷磺酸 / Perfluorooctane<br>sulfonates (PFOS-Acid, Metal Salt,<br>Amide)  | mg/kg        | 参考US EPA 3550C: 2007方法,以液相層析/質譜儀檢測./With reference to US EPA 3550C: 2007. Analysis was  | (MDL)<br>10 | No.1           |
| 全氟辛酸 / PFOA (CAS No.: 335-67-1)   | mg/kg        | performed by LC/MS.<br>参考US EPA 3550C: 2007方法,以液相層析/質譜儀檢測. / With reference to US<br>EPA 3550C: 2007. Analysis was<br>performed by LC/MS. | 10          | n.d.           |
| 六溴環十二烷及所有主要被辨别出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified ( $\alpha$ - HBCDD, $\beta$ - HBCDD, $\gamma$ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8)) | mg/kg        | 參考IEC 62321: 2008方法,以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.                             | 5           | n.d.           |
| 鹵素 / Halogen  |              |   | ***         |                |
| 鹵素(氟)/ Halogen-Fluorine (F)<br>(CAS No.: 14762-94-8)  | mg/kg        |   | 50          | n.d.           |
| 鹵素(氣)/ Halogen-Chlorine (Cl)<br>(CAS No.: 22537-15-1)   | mg/kg        | 参考BS EN 14582:2007, 以離子層析儀分析./ With reference to BS EN  | 50          | n.d.           |
| 鹵素(溴)/ Halogen-Bromine (Br)<br>(CAS No.: 10097-32-2)  | mg/kg        | 14582:2007. Analysis was performed by IC.   | 50          | n.d.           |
| 鹵素(碘)/ Halogen-Iodine (I) (CAS<br>No.: 14362-44-8)  | mg/kg        |   | 50          | n.d.           |

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## **Test Report**

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| 測試項目<br>(Test Items)             | 單位<br>(Unit) | 測試方法<br>(Method)  | 方法偵測<br>極限値<br>(MDL) | 結果<br>(Result)<br>No.1 |
|----------------------------------|--------------|---|----------------------|------------------------|
| 多溴聯苯總和 / Sum of PBBs             | mg/kg        |   |                      | n.d.                   |
| 一溴聯苯 / Monobromobiphenyl         | mg/kg        |   | 5                    | n.d.                   |
| 二溴聯苯 / Dibromobiphenyl           | mg/kg        |   | 5                    | n.d.                   |
| 三溴聯苯 / Tribromobiphenyl          | mg/kg        |   | 5                    | n.d.                   |
| 四溴聯苯 / Tetrabromobiphenyl        | mg/kg        |   | 5                    | n.d.                   |
| 五溴聯苯 / Pentabromobiphenyl        | mg/kg        |   | 5                    | n.d.                   |
| 六溴聯苯 / Hexabromobiphenyl         | mg/kg        |   | 5                    | n.d.                   |
| 七溴聯苯 / Heptabromobiphenyl        | mg/kg        |   | 5                    | n.d.                   |
| へ溴聯苯 / Octabromobiphenyl         | mg/kg        |   | 5                    | n.d.                   |
| 九溴聯苯 / Nonabromobiphenyl         | mg/kg        |   | 5                    | n.d.                   |
| 十溴聯苯 / Decabromobiphenyl         | mg/kg        | 参考IEC 62321: 2008方法,以氣相層析/<br>質譜儀檢測. / With reference to IEC<br>62321: 2008 and performed by GC/MS. | 5                    | n.d.                   |
| 多溴聯苯醚總和 / Sum of PBDEs           | mg/kg        |   | _                    | n.d.                   |
| 一溴聯苯醚 / Monobromodiphenyl ether  | mg/kg        |   | 5                    | n.d.                   |
| 二溴聯苯醚 / Dibromodiphenyl ether    | mg/kg        |   | 5                    | n.d.                   |
| 三溴聯苯醚 / Tribromodiphenyl ether   | mg/kg        |   | 5                    | n.d.                   |
| 四溴聯苯醚 / Tetrabromodiphenyl ether | mg/kg        |   | 5                    | n.d.                   |
| 五溴聯苯醚 / Pentabromodiphenyl ether | mg/kg        |   | 5                    | n.d.                   |
| 六溴聯苯醚 / Hexabromodiphenyl ether  | mg/kg        |   | 5                    | n.d.                   |
| 七溴聯苯醚 / Heptabromodiphenyl ether | mg/kg        |   | 5                    | n.d.                   |
| 八溴聯苯醚 / Octabromodiphenyl ether  | mg/kg        |   | 5                    | n.d.                   |
| 九溴聯苯醚 / Nonabromodiphenyl ether  | mg/kg        |   | 5                    | n.d.                   |
| 十溴聯苯醚 / Decabromodiphenyl ether  | mg/kg        |   | 5                    | n.d.                   |

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## **Test Report**

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#### 備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限値)
- 4. "-" = Not Regulated (無規格值)
- 5. \*\*= Qualitative analysis (No Unit) 定性分析(無單位)
- 6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
- 7. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個别單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

#### PFOS参考資訊(Reference Information): 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm),在半成品、成品或零部件中不得超過0.1%(1000ppm),在紡織品或塗層材料中不得超過1 $\mu$ g/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above  $1\mu g/m^2$ .)

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## **Test Report**

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

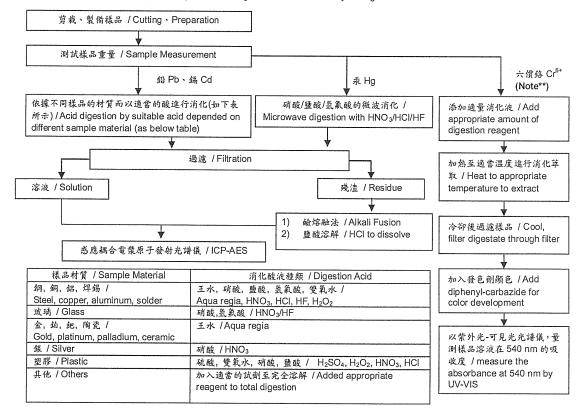
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。( 六價錦測試方法除外 ) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (  $Cr^{6*}$  test method excluded )
- 2) 测試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 测試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



Note\*\*:(1) 針對非金屬材料加入鹼性消化液,加热至 90~95℃萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95℃.

(2) 針對金屬材料加入純水,加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.

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西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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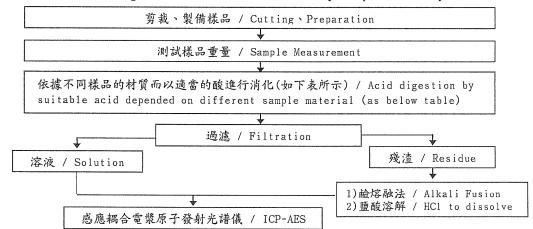
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 2) 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

#### 元素以 ICP-AES 分析的消化流程圖

(Flow Chart of digestion for the elements analysis performed by ICP-AES)



| 鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder    | 王水,硝酸,鹽酸,氫氟酸,雙氧水 /                    |
|---|---------------------------------------|
|   | Aqua regia, HNO3, HC1, HF, H2O2       |
| 玻璃 / Glass                                    | 硝酸,氫氟酸 / HNO:/HF                      |
| 金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic | 王水 / Aqua regia                       |
| 銀 / Silver                                    | 硝酸 / HNO3                             |
| 塑膠 / Plastic                                  | 硫酸,雙氧水,硝酸,鹽酸 / HzSO4, HzOz, HNO3, HC1 |
| 其他 / Others                                   | 加入適當的試劑至完全溶解 / Added appropriate      |
|   | reagent to total digestion            |

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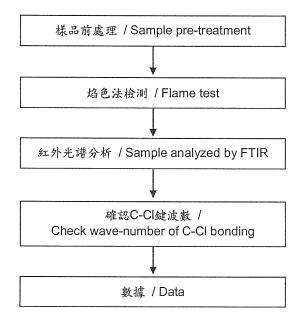
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#### 聚氯乙烯物質判定分析流程圖 /

#### Analysis flow chart for determination of PVC in material

- 測試人員:林建宇 / Name of the person who made measurement: Roy Lin
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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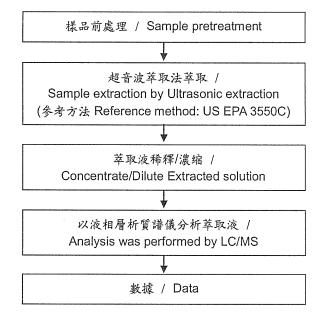
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#### 全氟辛酸/全氟辛烷磺酸分析流程圖 / PFOA/PFOS analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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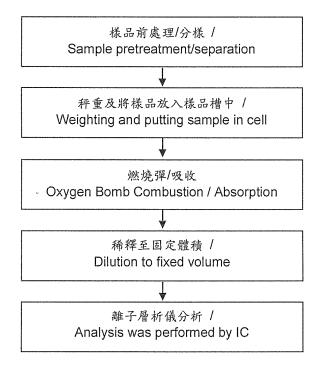
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#### 鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員:陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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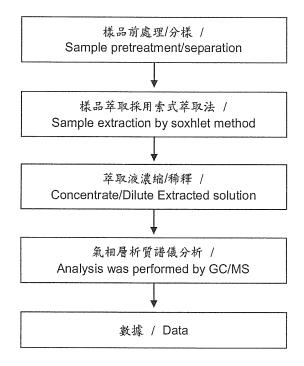
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#### 可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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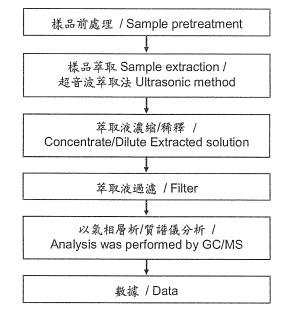
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#### 六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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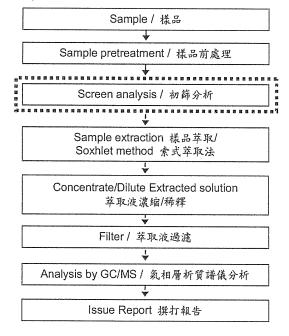
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#### 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員:翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

初次測試程序 / First testing process ————

確認程序 / Confirmation process - · - · ▶



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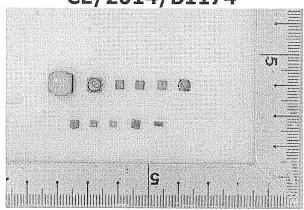
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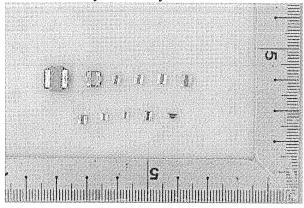
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(The tested sample / part is marked by an arrow if it's shown on the photo.)

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